54ACT11161, 74ACT11161
SYNCHRONOUS 4-BIT BINARY COUNTERS

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- **Inputs are TTL-Voltage Compatible**
- **Internal Look-Ahead for Fast Counting**
- **Carry Output for n-Bit Cascading**
- **Fully Synchronous Operation for Counting**
- **Synchronously Programmable**
- **Flow-Through Architecture to Optimize PCB Layout**
- **Center-Pin V_{CC} and GND Configurations to Minimize High-Speed Switching Noise**
- **EPIC™ (Enhanced-Performance Implanted CMOS) 1-μm Process**
- **500-mA Typical Latch-Up Immunity at 125°C**
- **Package Options Include Plastic “Small-Outline” Packages, Ceramic Chip Carriers, and Standard Plastic and Ceramic 300-mil DIPs**

description

This synchronous, presettable 4-bit binary counter features an internal carry look-ahead for application in high-speed counting designs. Synchronous operation is provided by having all flip-flops clocked simultaneously so that the outputs change coincident with each other when so instructed by the count-enable inputs and internal gating.

This mode of operation eliminates the output counting spikes that are normally associated with asynchronous (ripple clock) counters. A buffered clock input triggers the four flip-flops on the rising (positive-going) edge of the clock input waveform.

This counter is fully programmable; that is, it may be preset to any number between 0 and 5. As presetting is synchronous, setting up a low level at the load input disables the counter and causes the outputs to agree with the setup data after the next clock pulse regardless of the levels of the enable inputs.

The clear function for the ’ACT11161 is synchronous and a low level at the clear input sets all four of the flip-flop outputs low regardless of the levels of the clock, load, or enable inputs. This synchronous clear allows the count length to be modified easily by decoding the Q outputs for the maximum count desired. The active-low output of the gate used for decoding is connected to the clear input to synchronously clear the counter to 0000 (LLLL).

The carry look-ahead circuitry provides for cascading counters for n-bit synchronous applications without additional gating. Instrumental in accomplishing this function are two count-enable inputs and a ripple carry output. Both count-enable inputs (ENP and ENT) must be high to count, and ENT is fed forward to enable the ripple carry output (RCO). RCO thus enabled will produce a high-level pulse while the count is 15 (HHHH). This high-level overflow ripple carry pulse can be used to enable successive cascaded stages. Transitions at the ENP or ENT are allowed regardless of the level of the clock input.

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description (continued)

This counter features a fully independent clock circuit. Changes at control inputs (ENP, ENT, or $\overline{\text{LOAD}}$) that will modify the operating mode have no effect on the contents of the counter until clocking occurs. The function of the counter (whether enabled, disabled, loading, or counting) will be dictated solely by the conditions meeting the setup and hold times.

The 54ACT11161 is characterized for operation over the full military temperature range of – 55°C to 125°C. The 74ACT11161 is characterized for operation from – 40°C to 85°C.

logic symbol†

output sequence

Illustrated below is the following sequence:

1. Synchronously clear outputs to zero
2. Preset to binary twelve
3. Count to thirteen, fourteen, zero, one, and two
4. Inhibit.

logic diagram (positive logic)

logic symbol, each D/T flip-flop (positive logic)

logic diagram, each D/T flip-flop (positive logic)

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)‡

Supply voltage range, V_{CC}	−0.5 V to 7 V
Input voltage range, V_I (see Note 1)	−0.5 V to V_{CC} + 0.5 V
Output voltage range, V_O (see Note 1)	−0.5 V to V_{CC} + 0.5 V
Input clamp current, I_{IK} ($V_I < 0$ or $V_I > V_{CC}$)	± 20 mA
Output clamp current, I_{OK} ($V_O < 0$ or $V_O > V_{CC}$)	± 50 mA
Continuous output current, I_O ($V_O = 0$ to V_{CC})	± 50 mA
Continuous current through V_{CC} or GND pins	± 125 mA
Storage temperature range	−65°C to 150°C

‡ Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

recommended operating conditions

		54ACT11161		74ACT11161		UNIT
		MIN	MAX	MIN	MAX	
V_{CC}	Supply voltage	4.5	6.5	4.5	5.5	V
V_{IH}	High-level input voltage	2		2		V
V_{IL}	Low-level input voltage		0.8		0.8	V
V_I	Input voltage	0	V_{CC}	0	V_{CC}	V
V_O	Output voltage	0	V_{CC}	0	V_{CC}	V
I_{OH}	High-level output current		–24		–24	mA
I_{OL}	Low-level output current		24		24	mA
$\Delta t/\Delta v$	Input transition rise or fall rate	0	10	0	10	ns/V
T_A	Operating free-air temperature	–55	125	– 40	85	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	V_{CC}	T_A = 25°C			54ACT11161		74ACT11161		UNIT
			MIN	TYP	MAX	MIN	MAX	MIN	MAX	
V_{OH}	I_{OH} = – 50 μA	4.5 V	4.4			4.4		4.4		V
		5.5 V	5.4			5.4		5.4		
	I_{OH} = – 24 mA	4.5 V	3.94			3.7		3.8		
		5.5 V	4.94			4.7		4.8		
	I_{OH} = – 50 mA†	5.5 V				3.85				
	I_{OH} = – 75 mA†	5.5 V						3.85		
V_{OL}	I_{OL} = 50 μA	4.5 V			0.1		0.1		0.1	V
		5.5 V			0.1		0.1		0.1	
	I_{OL} = 24 mA	4.5 V			0.36		0.5		0.44	
		5.5 V			0.36		0.5		0.44	
	I_{OL} = 50 mA†	5.5 V					1.65			
	I_{OL} = 75 mA†	5.5 V							1.65	
I_I	$V_I = V_{CC}$ or GND	5.5 V			± 0.1		± 1		±1	μA
I_{CC}	$V_I = V_{CC}$ or GND, $I_O = 0$	5.5 V			8		160		80	μA
ΔI_{CC}‡	One input at 3.4 V, Other inputs at GND or V_{CC}	5.5 V			0.9		1		1	mA
C_i	$V_I = V_{CC}$ or GND	5 V		3.5						pF

† Not more than one output should be tested at a time, and the duration of the test should not exceed 10 ms.

‡ This is the increase in supply current for each input that is at one of the specified TTL voltage levels rather than 0 V to V_{CC}.

timing requirements over recommended operating free-air temperature range, V_{CC} = 5 V ± 0.5 V (unless otherwise noted)

			T_A = 25°C			54ACT11161		74ACT11161		UNIT
			MIN	TYP	MAX	MIN	MAX	MIN	MAX	
f_{clock}	Clock frequency									MHz
t_w	Pulse duration	CLK high or low								ns
		$\overline{\text{CLK}}$ low								
t_{su}	Setup time before CLK↑	A, B, C, D								ns
		$\overline{\text{LOAD}}$								
		ENP, ENT								
		$\overline{\text{CLR}}$ inactive								
		$\overline{\text{CLR}}$ low								
		CLR (high) inactive								
t_h	Hold time, all synchronous inputs after CLK↑									ns

switching characteristics over recommended operating free-air temperature range, V_{CC} = 5 V ± 0.5 V (unless otherwise noted) (see Note 2)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	T_A = 25°C			54ACT11161		74ACT11161		UNIT
			MIN	TYP	MAX	MIN	MAX	MIN	MAX	
f_{max}										MHz
t_{PLH}	CLK	RCO								ns
t_{PHL}										
t_{PLH}	CLK	Any Q								ns
t_{PHL}										
t_{PLH}	ENT	RCO								ns
t_{PHL}										
t_{PLH}	CLR	Any Q								ns
t_{PHL}		RCO								

NOTE 2: Load circuits and voltage waveforms are shown in Section 1 of *Advanced CMOS Logic Data Book*, 1990

operating characteristics, V_{CC} = 5 V, T_A = 25°C

PARAMETER		TEST CONDITIONS	TYP	UNIT
C_{pd}	Power dissipation capacitance	C_L = 50 pF, f = 1 MHz		pF

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